

described as they offer potential solutions which are more similar to digital test methods. Finally, in Design-for-Testability and Built-In-Self-Test, two other concepts that were taken from digital design, are introduced in an analog context and illustrated for the case of integrated filters. In summary, the purpose of this book is to provide a glimpse on recent research results in the area of testing mixed-signal integrated circuits, specifically in the topics mentioned above. Much of the work reported herein has been performed within cooperative European Research Projects, in which the authors of the different chapters have actively collaborated. It is a representative snapshot of the current state-of-the-art in this emergent field.

The continual explosion of computer development has led to inadequate coverage of proper & useful on-line testing techniques. This text fills the gap in the literature by presenting the latest techniques available for digital devices used in the most popular computers. Initial chapters explore the classic problems of on-line testing, pointing out the limited applications of conventional approaches to the problem of diagnosing digital devices using LSI & VLSI chips. Chapters 4-7 cover compact testing methods used to diagnose complex digital circuits. Chapters 8 & 9 analyze the techniques of compressing output responses of a digital circuit, while chapter 10 surveys promising recent signature generation techniques for binary sequences. The final chapter covers multi-output digital circuits.

Using the book and the software provided with it, the reader can build his/her own tester arrangement to investigate key aspects of analog-, digital- and mixed system circuits Plan of attack based on traditional testing, circuit design and circuit manufacture allows the reader to appreciate a testing regime from the point of view of all the participating interests Worked examples based on theoretical bookwork, practical experimentation and simulation exercises teach the reader how to test circuits thoroughly and effectively

This book facilitates the VLSI-interested individuals with not only in-depth knowledge, but also the broad aspects of it by explaining its applications in different fields, including image processing and biomedical. The deep understanding of basic concepts gives you the power to develop a new application aspect, which is very well taken care of in this book by using simple language in explaining the concepts. In the VLSI world, the importance of hardware description languages cannot be ignored, as the designing of such dense and complex circuits is not possible without them. Both Verilog and VHDL languages are used here for designing. The current needs of high-performance integrated circuits (ICs) including low power devices and new emerging materials, which can play a very important role in achieving new functionalities, are the most interesting part of the book. The testing of VLSI circuits becomes more crucial than the designing of the circuits in this nanometer technology era. The role of fault simulation algorithms is very well explained, and its implementation using Verilog is the key aspect of this book. This book is well organized into 20 chapters. Chapter 1 emphasizes on uses of FPGA on various image processing and biomedical applications. Then, the descriptions enlighten the basic understanding of digital design from the perspective of HDL in Chapters 2-5. The performance enhancement with alternate material or geometry for silicon-based FET designs is focused in Chapters 6 and 7. Chapters 8 and 9 describe the study of bimolecular interactions with biosensing FETs. Chapters 10-13 deal with advanced FET structures available in various shapes, materials such as nanowire, HFET, and their comparison in terms of device performance metrics calculation. Chapters 14-18 describe different application-specific VLSI design techniques and challenges for analog and digital circuit designs. Chapter 19 explains the VLSI testability issues with the description of simulation and its categorization into logic and fault simulation for test pattern generation using Verilog HDL. Chapter 20 deals with a secured VLSI design with hardware obfuscation by hiding the IC's structure and function, which makes it much more difficult to reverse engineer.

With Emphasis on Testable Semicustom Circuits

Digital Systems Testing and Testable Design

Test and Design-for-Testability in Mixed-Signal Integrated Circuits

Digital Logic Design

Testing of Digital Systems

Enables the reader to test an analog circuit that is implemented either in bipolar or MOS technology. Examines the testing and fault diagnosis of analog and analog part of mixed signal circuits. Covers the testing and fault diagnosis of both bipolar and Metal Oxide Semiconductor (MOS) circuits and introduces . Also contains problems that can be used as quiz or homework.

Your road map for meeting today's digital testing challenges Today, digital logic devices are common in products that impact public safety, including applications in transportation and human implants. Accurate testing has become more critical to reliability, safety, and the bottom line. Yet, as digital systems become more ubiquitous and complex, the challenge of testing them has become more difficult. As one development group designing a RISC stated, "the work required to . . . test a chip of this size approached the amount of effort required to design it." A valued reference for nearly two decades, Digital Logic Testing and Simulation has been significantly revised and updated for designers and test engineers who must meet this challenge. There is no single solution to the testing problem. Organized in an easy-to-follow, sequential format, this Second Edition familiarizes the reader with the many different strategies for testing and their applications, and assesses the strengths and weaknesses of the various approaches. The book reviews the building blocks of a successful testing strategy and guides the reader on choosing the best solution for a particular application. Digital Logic Testing and Simulation, Second Edition covers such key topics as: * Binary Decision Diagrams (BDDs) and cycle-based simulation * Tester architectures/Standard Test Interface Language (STIL) * Practical algorithms written in a Hardware Design Language (HDL) * Fault tolerance * Behavioral Automatic Test Pattern Generation (ATPG) * The development of the Test Design Expert (TDX), the many obstacles encountered and lessons learned in creating this novel testing approach Up-to-date and comprehensive, Digital Logic Testing and Simulation is an important resource for anyone charged with pinpointing faulty products and assuring quality, safety, and profitability.

Modern electronics testing has a legacy of more than 40 years. The introduction of new technologies, especially nanometer technologies with 90nm or smaller geometry, has allowed the semiconductor industry to keep pace with the increased performance-capacity demands from consumers. As a result, semiconductor test costs have been growing steadily and typically amount to 40% of today's overall product cost. This book is a comprehensive guide to new VLSI Testing and Design-for-Testability techniques that will allow students, researchers, DFT practitioners, and VLSI designers to master quickly System-on-Chip Test architectures, for test debug and diagnosis of digital, memory, and analog/mixed-signal designs. Emphasizes VLSI Test principles and Design for Testability architectures, with numerous illustrations/examples. Most up-to-date coverage available, including Fault Tolerance, Low-Power Testing, Defect and Error Tolerance, Network-on-Chip (NOC) Testing, Software-Based Self-Testing, FPGA Testing, MEMS Testing, and System-In-Package (SIP) Testing, which are not yet available in any testing book. Covers the entire spectrum of VLSI testing and DFT architectures, from digital and analog, to memory circuits, and fault diagnosis and self-repair from digital to memory circuits. Discusses future nanotechnology test trends and challenges facing the nanometer design era; promising nanotechnology test techniques, including Quantum-Dots, Cellular Automata, Carbon-Nanotubes, and Hybrid Semiconductor/Nanowire/Molecular Computing. Practical problems at the end of each chapter for students. This book introduces several novel approaches to pave the way for the next generation of integrated circuits, which can be successfully and reliably integrated, even in safety-critical applications. The authors describe new measures to address the rising challenges in the field of design for testability, debug, and reliability, as strictly required for state-of-the-art circuit designs. In particular, this book combines formal techniques, such as the Satisfiability (SAT) problem and the Bounded Model Checking (BMC), to address the arising challenges concerning the increase in test data volume, as well as test application time and the required reliability. All methods are discussed in detail and evaluated extensively, while considering industry-relevant benchmark candidates. All measures have been integrated into a common framework, which implements standardized software/hardware interfaces.

Using HDL Models and Architectures

VLSI Testing

Digital Logic Testing and Simulation

Fault Diagnosis of Analog Integrated Circuits

A Testability Measure for Register-transfer Level Digital Circuits

This book is a self-contained introduction to all aspects of microelectronic (IC) testing. It includes the theory necessary for advanced students as well as reference to industrial practice and economics that will interest designers in industry. Chapters cover both digital circuit testing and the growing area of mixed circuits, used particularly in signal processing.

In today's digital design environment, engineers must achieve quick turn-around time with ready accesses to circuit synthesis and simulation applications. This type of productivity relies on the principles and practices of computer aided design (CAD). Digital Design: Basic Concepts and Principles addresses the many challenging issues critical to today's digital design practices such as hazards and logic minimization, finite-state-machine synthesis, cycles and races, and testability theories while providing hands-on experience using one of the industry's most popular design application, Xilinx Web PACKTM. The authors begin by discussing conventional and unconventional number systems, binary coding theories, and arithmetic as well as logic functions and Boolean algebra. Building upon classic theories of digital systems, the book illustrates the importance of logic minimization using the Karnaugh map technique. It continues by discussing implementation options and examining the pros and cons of each method in addition to an assessment of tradeoffs that often accompany design practices. The book also covers testability, emphasizing that a good digital design must be easy to verify and test with the lowest cost possible. Throughout the text, the authors analyze combinational and sequential logic elements and illustrate the designs of these components in structural, hierarchical, and behavior VHDL descriptions. Covering fundamentals and best practices, Digital Design: Basic Concepts and Principles provides you with critical knowledge of how each digital component ties together to form a system and develops the skills you need to design and simulate these digital components using modern CAD software.

In the last few years CMOS technology has become increasingly dominant for realizing Very Large Scale Integrated (VLSI) circuits. The popularity of this technology is due to its high density and low power requirement. The ability to realize very complex circuits on a single chip has brought about a revolution in the world of electronics and computers. However, the rapid advancements in this area pose many new problems in the area of testing. Testing has become a very time-consuming process. In order to ease the burden of testing, many schemes for designing the circuit for improved testability have been presented. These design for testability techniques have begun to catch the attention of chip manufacturers. The trend is towards placing increased emphasis on these techniques. Another byproduct of the increase in the complexity of chips is their higher susceptibility to faults. In order to take care of this problem, we need to build fault-tolerant systems. The area of fault-tolerant computing has steadily gained in importance. Today many universities offer courses in the areas of digital system testing and fault-tolerant computing. Due to the importance of CMOS technology, a significant portion of these courses may be devoted to CMOS testing. This book has been written as a reference text for such courses offered at the senior or graduate level. Familiarity with logic design and switching theory is assumed. The book should also prove to be useful to professionals working in the semiconductor industry.

The summer school on VLSI GAD Tools and Applications was held from July 21 through August 1, 1986 at Beatenberg in the beautiful Bernese Oberland in Switzerland. The meeting was given under the auspices of IFIP WG 10. 6 VLSI, and it was sponsored by the Swiss Federal

Institute of Technology Zurich, Switzerland. Eighty-one professionals were invited to participate in the summer school, including 18 lecturers. The 81 participants came from the following countries: Australia (1), Denmark (1), Federal Republic of Germany (12), France (3),

Italy (4), Norway (1), South Korea (1), Sweden (5), United Kingdom (1), United States of America (13), and Switzerland (39). Our goal in the planning for the summer school was to introduce the audience into the realities of CAD tools and their applications to VLSI design.

This book contains articles by all 18 invited speakers that lectured at the summer school. The reader should realize that it was not intended to publish a textbook. However, the chapters in this book are more or less self-contained treatments of the particular subjects.

Chapters 1 and 2 give a broad introduction to VLSI Design. Simulation tools and their algorithmic foundations are treated in Chapters 3 to 5 and 17. Chapters 6 to 9 provide an excellent treatment of modern layout tools. The use of CAD tools and trends in the design of

32-bit microprocessors are the topics of Chapters 10 through 16. Important aspects in VLSI testing and testing strategies are given in Chapters 18 and 19.

Digital Integrated Circuits

System-on-Chip Test Architectures

Modern Techniques

Design of Logic Systems

Testing Digital Circuits

An Introduction to Logic Circuit Testing provides a detailed coverage of techniques for test generation and testable design of digital electronic circuits/systems. The material covered in the book should be sufficient for a course, or part of a course, in digital circuit testing for senior-level undergraduate and first-year graduate students in Electrical Engineering and Computer Science. The book will also be a valuable resource for engineers working in the industry. This book has four chapters. Chapter 1 deals with various types of faults that may occur in very large scale integration (VLSI)-based digital circuits. Chapter 2 introduces the major concepts of all test generation techniques such as redundancy, fault coverage, sensitization, and backtracking. Chapter 3 introduces the key concepts of testability, followed by some ad hoc design-for-testability rules that can be used to enhance testability of combinational circuits. Chapter 4 deals with test generation and response evaluation techniques used in BIST (built-in self-test) schemes for VLSI chips. Table of Contents: Introduction / Fault Detection in Logic Circuits / Design for Testability /

Built-in Self-Test / References

VLSI Test Principles and Architectures

Essentials of Electronic Testing for Digital, Memory and Mixed-Signal VLSI Circuits

Notes, Observations and Improvements in the Area of Digital Circuit Testing and Testability

Digital Integrated Circuit Design Using Verilog and Systemverilog

VLSI CAD Tools and Applications